Ain Shams University College of Women (Arts, Science and Education) Physics Department



Study of Some Physical Properties of 5,10,15.20tetraphenyl-21H,23H-porphine iron choloride (FeTPPCI) Thin Films and Their Photovoltaic Application

A thesis submitted for the degree of M.SC Degree in Physics (Solid state physics)

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القمر 49

Contents

Acknowledge	ment	i
List of Figure	es	ii
List of Table	s	VII
Abstract		X
	Chapter 1	
	Chapter 1	
In	ntroduction and Literature Review	
1.1.1 F 1.1.2 I 1.1.3 S	emiconductor Basic Properties of Organic Semiconductors Deposition Techniques Semiconducting Properties of Organic Materials and of Porphyrins	1 2 2 3 6
1.3 5,10,15, 20 (FeTPPC) 1.4 Literature	,	9 10
	Chapter 2	
	Theoretical Background	
2.1.1 M	roperties of organic semiconductors lechanisms of optical absorption he absorption coefficient and the optical band gap	21 22 24
2.1.3 Dispersi 2.2 Electric p 2.2.1. I	on in semiconductor materials oroperties Oc electric conductivity	26 31 31
2.3 I-V chara	.1.1 Dc analyses acteristics of metal/semiconductor contacts Electronic structure of organic / metal interfaces	31 33 33
2.4 Photovolt	aic of organic materials	35
2.4.1 2.4.2 2.4.3	Short Circuit Current, Open Circuit Voltage	37 39
2.4.4	and Fill Factor Photoresponsivity, External Quantum Efficiency and Power Conversion Efficiency	40 42
2.4.5	•	43

Chapter 3 Experimental techniques

3.1 Preparation of FeTPPCl thin films	52
3.1.1Substrat cleaning	
3.1.2. Method of thin films preparation.	
3.2 Film thickness measurements	
3.2.1 Quartz crystal thickness monitor	
3.2.2 Interferometric method	
3.3 Structural investigation of FeTPPCl	58
3.3.1 X-ray diffractometry (XRD) technique	58
3.3.2 Transmission electron microscope (TEM)	59
3.3.3 Infrared spectroscopy technique	60
3.4 Optical measurements	61
3.4.1 Film transmittance and reflectance	61
3.4.2 Determination of the optical constants	63
3.5 Electrical measurements	64
3.5.1 Planar thin film samples preparation	64
3.5.2 Devices preparation and measurements	65
3.5.2.1 Hybrid organic—inorganic device preparation	
and measurements	65
3.5.2.2 Current density-voltage (J-V-T) Measurements	65
• • • •	
Chapter 4	
Result and disscution	
Result and disscution	
	m
Result and disscution 4.1 Structural investigation of FeTPPCl in powder and thin fill forms.	m 67
4.1 Structural investigation of FeTPPCl in powder and thin fill forms.	67
4.1 Structural investigation of FeTPPCl in powder and thin film forms.4.1.1 X-ray diffraction studies of FeTPPCl in powder form	
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 	67 67
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4. 2 Optical properties of FeTPPCl thin films 	67 67 69
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4. 2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of 	67 67 69 71
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4. 2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of FeTPPCl thin films. 	67 67 69
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4. 2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of FeTPPCl thin films. 4.2.2 Influence of illumination on the optical properties of 	67 67 69 71 72
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4. 2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of FeTPPCl thin films. 	67 67 69 71
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4.2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of FeTPPCl thin films. 4.2.2 Influence of illumination on the optical properties of FeTPPCl thin films . 	67 67 69 71 72
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4. 2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of FeTPPCl thin films. 4.2.2 Influence of illumination on the optical properties of 	67 67 69 71 72
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4.2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of FeTPPCl thin films. 4.2.2 Influence of illumination on the optical properties of FeTPPCl thin films . 	67 67 69 71 72 80
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4. 2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of FeTPPCl thin films. 4.2.2 Influence of illumination on the optical properties of FeTPPCl thin films . Chapter 5 Vibrational spectroscopic analysis of FeTPPC 	67 67 69 71 72 80
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4. 2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of FeTPPCl thin films. 4.2.2 Influence of illumination on the optical properties of FeTPPCl thin films . Chapter 5	67 67 69 71 72 80
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4.2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of FeTPPCl thin films. 4.2.2 Influence of illumination on the optical properties of FeTPPCl thin films . Chapter 5 Vibrational spectroscopic analysis of FeTPPC experimental and theoretical (DFT methode) steps 	67 67 69 71 72 80
 4.1 Structural investigation of FeTPPCl in powder and thin film forms. 4.1.1 X-ray diffraction studies of FeTPPCl in powder form 4.1.2 Transimation electron microscope studies (TEM) 4. 2 Optical properties of FeTPPCl thin films 4.2.1 Influence of γ- irradiation on the optical prorties of FeTPPCl thin films. 4.2.2 Influence of illumination on the optical properties of FeTPPCl thin films . Chapter 5 Vibrational spectroscopic analysis of FeTPPC 	67 69 71 72 80

5.2.1 Molecular Mechanics	89
5.2.2 Electronic Structure Method	90
5.2.2.1 Semi-Empirical Method	90
5.2.2.2 ab Initio Method	90
5.3 The ab Initio Modeling Program Package	90
5.3.1Gaussian 03 Package	90
5.4 Computational Details	90
5.4.1 Vibrational Assignments	92
5.4.1.1 C–H Vibrations	93
5.4.1.2 C=C Vibrations	94
5.4.1.3 C=N Vibrations	95
5.4.1.4 Fe-Cl Vibrations	95
5.4.2 Other Molecular Properties	96

Chapter 6 Electrical properties

6.1 DC electrical conductivity investigation of thin films	99
6.2 Electrical properties of FeTPPCl on p- Si heterojunction	101
6.2.1 Dark current – voltage characteristic6.2.2 Current – Voltage characteristicsof Au/FeTPPCl/p-Si	101
under illumination	109
Conclusion	111
References	113
Arabic summary	1

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List of Figures

Fig. 1.1.Different hybridizations for the carbon atom.	4
Fig. 1.2.Schematical representation of the splitting of two 2p orbitals into	
a bonding molecular π -orbital and an anti-bonding molecular $\pi*$ -orbital.	
Increasing the number of carbon atoms, leads to more degeneration and the	
formation of quasi-continuous bands of occupied and unoccupied states.	6
Fig.1.3 The molecular structure of FeTPPCl.	9
Fig.1.4 Model of the statistically averaged molecule of FeTPPCl according to	
Hoard et al.	17
Fig. 1.5 The asymmetric unit of FeTPPCl. On the left is an enlargement in which	h one
can see the apparent torsional motion of C8 and C9. On the right are sh	iown
the intramolecular bond lengths and angles.	18
Fig 2.1.Schematic sketch of the typical behavior of light passing through a thin	film on
a substrate.	22
Fig 2.2.The incoming radiation Io results in reflectance R and transmittance T.	23
Fig. 2.3 Schematic illustration of semiconductor interband transitions: (a) direct	
transition and (b) indirect transition.	25
Fig.2.4. Models of organic/metal interfaces. Both take account of the interfacial	dipole
layer. As for band bending (a) assumes band bending leading to Fermi level	
alignment, while observed results (b) show no such band bending.	34
Fig. 2.5. Schematic diagrams of a conventional p-n junction solar cell and or	ganic
heterojunction solar cell.	37
Fig. 2.6.The Equivalent circuit of an ideal solar cell (full lines). Non-ideal comp	onents
are shown by the dotted line.	38
Fig. 2.7. Graph of current versus voltage for photovoltaic devices. The figure si	hows
how the device characteristics change upon illumination.	41

- Fig. 2.8.Metal-insulator-metal (MIM) picture of organic diode device function.
 - (a) Closed circuit condition: under illumination photogenerated charges drift toward the contacts.
 - (b) Flat band or open circuit condition: the current becomes zero.
 - (c) Reversed bias: photogenerated charges drift in strong electric fields, the diode operates as a photodetector.
 - (d) Forward bias larger than VOC: the injection increases and the diode openup.45
- Fig. 2.9.Schematic of a single layer device with a Schottky contact at the aluminum contact. Photogenerated excitons can only be dissociated in a thin depletion layer W, and thus the device is exciton diffusion limited.
- Fig.2.10.Representation of donor/acceptor interface architecture possibilities:

 (a) a planar heterojunction, formed between thin films of donor and acceptor materials,(b)an optimal bulk heterojunction, where there is complete phase separation of donor to one side and acceptor to the other side of the device structure; and (c) a non-ideal bulk heterojunction, where isolated regions of donor and/or acceptor phases prevent the collection of photogenerated charges. Dashed (solid) lines correspond to hole (electron) transport, and the arrow("x") represents continuing (terminated) charge carrier flow. 47
- Fig. 2.11.Schematic energy level diagram of an organic heterojunction between a donor (D) and an acceptor (A) layer. Here IP (or highest occupied molecular orbital (HOMO)) and EA (or lowest unoccupied molecular orbital (LUMO)) are the ionization potential and electron affinity, respectively. The exciton binding energy (EB) of each material is equal to the difference between the transport gap (Etran) and optical gap (Eopt). The vacuum energy (Evac) is shown and is the point of zero energy, with the y-axis defined as the energy axis. The process of charge transfer of an exciton from D → A is also illustrated.
- Fig. 2.12 Schematic of a bulk heterojunction device. The donor (D) is blended with the acceptor (A) throughout the whole film. Thus, photogenerated excitons can be dissociated into charges at any place

 49

Fig.2.13 Donor and acceptor materials may be blended together to yield a disp	ersed
heterojunction. If the domain size in the blend is similar to the ex-	xciton
diffusion length, then the probability that an exciton will reach the inte	erface
and dissociate is high. For efficient photocurrent collection, each ma	aterial
must provide a continuous path for the transport of separated charge	to the
contacts. Isolated domains can trap charges, causing recombin	ation.
(a) A blend of two polymers. (b) A blend of one polymer with ele	ectron
accepting nano particles or fullerenes. The concentration of nano particles	rticles
should be sufficient to allow percolation.	51
Fig.3.1 The molecular structure of FeTPPCl	53
Fig. 3.2 Thermal evaporation process	55
Fig. 3.3.(a) Schematic diagram of the interferometer; (b) Schematic diagram show	ing
the optical set-up for film thickness measurements; (c) Fizeau fringes.	57
Fig. 3.4Schematic of an FTIR system	60
Fig. 3.5 Schematic diagram showing the spectrophotometer	61
Fig. 3.6 Measurements of film transmittance where the reference is clean substrate.	62
Fig. 3.7 Measurements of film reflectance according to the reference (Almirror)	63
Fig. 3.8 Schematic representation of measuring configuration used for electrical	
measurements of FeTPPCl films in planner configuration.	64
Fig. 3.9 Schematic structure of Au/FeTPPCl/p-Si/Al cell	65
Fig.3.10 (a) Circuit for monitoring the I-V characteristics using CRO.	
(b) Circuit for measuring the I-V characteristics point by point in dark and un	der
illumination	66
Fig. 4.1. XRD of FeTPPCl in: (a) the powder form, (b) as-deposited (c) γ-irradiate	d
thin film.	68

Fig. 4.3 The spectral dependence of the normal incidence transmittance,	1 and
reflectance, R for the as-deposited and γ -irradiated (1,5,10 kGy) F	FeTPPC1 thin
film of thickness 130 nm.	72
Fig. 4.4 The spectral dependence of the real part of refractive index, $n(\lambda)$.), for the as
deposited and γ-irradiated (1,5,10 kGy) FeTPPCl thin film of th	ickness
130 nm	73
Fig 4.5. The spectral dependence of the imaginary part of refractive index	$k(\lambda)$, for
the as-deposited and γ -irradiated (1,5,10 kGy) FeTPPCl thin film	of thickness
130 nm	74
Fig. 4.6 Spectral behavior of absorption coefficient, α , for the as-deposite	ed and γ
irradiated (1,5,10 kGy) FeTPPCl thin film of thickness 130 nm.	75
Fig. 4.7 Relation between (αhυ)1/2 and photon energy (hυ) for as-deposit	ited and γ
Irradiated FeTPPCl thin films.	76
Fig. 4.8 Variation of the energy gaps $\frac{E_g^{opt}}{g}$ and Eg with γ -irradiation dose	es of FeTPPC
thin films.	77
Fig. 4.9 Relation between $(n2-1)-1$ and $(hv)2$ for the as-deposited and	γ-irradiated
FeTPPCl thin films.	79
Fig.4.10 Relation between n2 and $\lambda 2$ for the as-deposited and γ -irradiated	d FeTPPCl
Thin films .	79
Fig 4.11-a Spectral dependences of optical transmittance T calculated for	: as-deposited
and illuminated FeTPPCl thin films	80
Fig 4.11-b Spectral dependences of optical reflectance R calculated for a	s- deposited
and illuminated FeTPPCl thin films	81
Fig. 4.12(a) Spectral behaviour of real part of refractive index, n, for as-	leposited and

Fig.4.2 TEM micrograph for (a) the as-deposited (b)γ-irradiated (10 kGy) FeTPPCl

70

thin films.

Illuminated FeTPPCl thin films.	82
Fig 4.12 (b) Dependences of absorption coefficient α upon the photon energy hv	, as
calculated for as-deposited and illuminated FeTPPCl thin films.	82
Fig.4.13 (a,b&c) Dependence of molar extinction coefficient on the wave number	er
obtained experimentally for as-deposited and illuminated FeTPPCl thin	n films
(black circles) and its theoretical fit (red solid line) that assumes four	
oscillator components with Gaussian profiles. Blue lines correspond to	
decomposition of the spectrum into these Gaussian components.	84
Fig.4.14 Relation between $(\alpha h \upsilon)1/2$ and photon energy $(h \upsilon)$ calculated for as	
Deposited and illuminated FeTPPCl thin films.	86
Fig.4.15 Relation between $(n2-1)-1$ and (hv) 2calculated for as-deposited and	
Illuminated FeTPPCl thin films.	87
Fig.4.16 Relation between n2 and $\lambda 2$ calculated for as-deposited and illuminated	
FeTPPCl thin films.	88
Fig. 5.1. Optimized molecular structure of FeTPPCl at B3LYP/6-311g basis set.a	a) side
view b) top view.	92
Fig.5.2 Experimenal FT-IR spectrum for FeTPPCl (a) in Powder form, and (b)	Thin
film form and calculated FT-IR spectrum for FeTPPCl (c) at B3LYP/6-3	1g
basis set and (d) at B3LYP/6-311g basis set.	94
Fig. 5.3. Calculated HOMO-LUMO frontier molecular orbitals for FeTPPCl at	
B3LYP/6-311g basis set.	98
Fig.6.1:Temperature dependence of σDC for the as-deposited and γ -irre	adiated
FeTPPCl thin films.	100
Fig.6.2 J-V-T characteristics for Au/FeTPPCl/p- Si/Al at different temperatures in	
forward and reverse conditions. 101	

Fig.6.4 Variation of ln(Io/T2) versus 1000/T for Au/Alq3/p-Si/Al heterojunction . 103

Fig.6.3 Dark J-Vcharacteristics of Au/FeTPPCl/p-Si/Al at different temperatures in

102

forward bias.

Fig. 6.5 Temperature dependence of the ideality factor, \mathbf{n} , and the zero barrier h	neigh
Φ_{bo} , for FeTPPCl/ p-Si.	104
Fig. 6.6. Junction resistance (R $_{\rm j}$) vs. V for FeTPPCl /p-Si heterojunction at 298 K.	104
Fig.6.7 Plot of [dV/d(lnI)] versus I at different temperatures.	106
Fig.6.8 Plot of H(I) and I at different temperatures for FeTPPCl/p-Si.	106
Fig.6.9 Variation of ln(J) with ln (V) at higher forward voltage bias.	108
Fig.6.10. the temperature dependence of ln (J) at 1.5 V	108
Fig.6.11 Temperature dependence of ln(IR) for FeTPPCl/p-Si	109
Fig.6.12 I-V characteristics under an illumination (10 mW/cm2) for FeTPPCl/p-Si	110

List of Tables

Table 4.1.Experimental and calculated data of FeTPPCI compound.	09
Table 4.2 position peak of absorption	76
Table 4.3 position peak of dispertion	76
Table 4.4: Optical parameters for the as-deposited and γ -irradiated FeTPPC1	
thin films.	80
Table 4.5 position peak of absorption	83
Table 4.6 position peak of dispertion	83
Table 4.7: Peak position, oscillator strengths ,f and electric dipole strengths,q2	
,calculated for the three Gaussian peaks, as obtained for as-deposited and illum	ninated
FeTPPCl thin films.	86
Table 5.1. Experimental and selected Calculated Vibrational Wavenumbers (H	Harmonic
Frequency (cm-1)), IR Intensities and Assignments for FeT	PPCl at
B3LYP/6-311G basis set.	96
Table 5.2. Optimized calculations of HOMO–LUMO energy gap (eV) for Fe	TPPCl at
B3I VP/6-31G and B3I VP/6-311G hasis sets	97

Abstract

Solar energy is widely believed to be the most promising renewable energy source to fulfill the ever-increasing energy demand from human society now and into the future. Innovation in solar cell design is required to reduce cost and compete with traditional power generation. Current innovative solar technologies include nanostructured dye- sensitised solar cells and polymer solar cells, which both contain organic materials. One these groups of materials, organic molecules with conjugated π electron systems, such as porphyrin molecules, have created a new materials that offer a new applications in solar cell technology. One of these materials is 5,10,15, 20-tetraphenyl -21H, 23H- porphine iron (III) chloride (FeTPPCI).Organic solar cells have been explored as a potentially low-cost alternative to silicon solar cell due to their lower fabrication costs compared to crystalline.

This thesis is focused on the study of the structural , optical and Dc electrical properties of FeTPPCl in thin film form which prepared by thermal evaporation technique. The structural of powder and as-deposited and irradiated thin films of FeTPPCl are investigated by X-ray diffraction technique and Transmation electron microscope (TEM). The results indicate the polycrystalline nature of the powder form and as-deposited and irradiated films. The analysis of XRD diffraction pattern indicates that FeTPPCl has a tetragonal structure with lattice constants of a = 13.53 Å and c= 9.82 Å and with space group (I4/m, Z=2). The transimation electron microscope (TEM) showed spherical nanoparticles with average diameter 16 nm of the as- deposited thin films. Aggregation of the FeTPPCl nanoparticles is observed with different shapes as a result of γ -irradiation.

The optical transmittance, T, and the reflectance, R, spectra of the as-deposited, irradiated and illuminated thin films will measured in the spectral range 200–2500 nm. The obtained data of optical constants (refracted index n, extinction coefficient, k and absorption coefficient(α)were used to determin types of transition and the optical energy gaps E_g^{opt} , and the fundamental bandgap E_g for thin films before and after γ -irradiation and illumination. It was found that all films exhibited indirect allowed inter-band transitions. The indirect energy gap were affected by the dose of γ -irradiation and the time of illumination. It was found that the values of